



Image 2877 #

500.40120X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): T. OTSUBO, et al
Serial No.: 09/855,674
Filed: May 16, 2001
For: APPARATUS FOR MONITORING THICKNESS OF
DEPOSITED LAYER IN REACTOR AND DRY PROCESSING
METHOD
Group: 2877
Examiner: K. Brown

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Mail Stop DD
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

November 12, 2003

Sir:

In the matter of the above-identified application, applicant(s) is/are submitting herewith a copy of a communication from a foreign patent office in a counterpart foreign application and copies of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

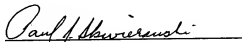
This information disclosure statement is being submitted before the mailing date of either a final action or a notice of allowance and is accompanied by the fee of \$180.00 set forth in 37 CFR 1.17(p).

To the extent that, the documents listed on the attached form equivalent to Form PTO-1449, are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language abstract of the document.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account No. 01-2135 (500.40120X00) and please credit any excess fees to such deposit account.

Respectfully submitted,

A handwritten signature in cursive script, appearing to read "Paul J. Skwierawski", is written over a horizontal line.

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Form PTO-1449
Equivalent

U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No. 500.40120X00
Serial No. 09/855,674
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U.S. Patent Documents

| Examiner Initials | Document No. | Date | Name | Class Subclass | Filing Date If Approp. |
|----------------------|-----------------|------|------|----------------|---------------------------|
|----------------------|-----------------|------|------|----------------|---------------------------|

Foreign Patent Documents

| Document No. | Date | Country | Class Subclass | Translation Yes No |
|-----------------|-------|---------|----------------|-----------------------|
| 61-183919 | 8/86 | Japan | | (abstract) |
| 8-276657 | 10/96 | Japan | | (abstract) |
| 9-036102 | 2/97 | Japan | | (abstract) |
| 11-297629 | 10/99 | Japan | | (abstract) |

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner

Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609;
Draw line through citation if not in conformance and not considered. Include copy of this form with next
communication to applicant.